

<b>Notice of References Cited</b>	Application/Control No. 10/519,933	Applicant(s)/Patent Under Reexamination IWASA ET AL.	
	Examiner Mark Ruthkosky	Art Unit 1745	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,122,277	10-2006	Morioka et al.	429/213
*	B	US-2005/0170247	08-2005	Nakahara et al.	429/213
*	C	US-6,866,964	03-2005	Nakahara et al.	429/213
*	D	US-2004/0248004	12-2004	Iwasa et al.	429/213
*	E	US-2004/0115529	06-2004	Nakahara et al.	429/213
*	F	US-2003/0044681	03-2003	Morioka et al.	429/213
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2002-117,854	04-2002	JPO	Sato	H01M 4/60
	O	JP-2002-304,996	10-2002	JPO	Nakahara	H01M 4/60
	P	WO 02/082570	10-2002	PCT	Nakahara	H01M 4/60
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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